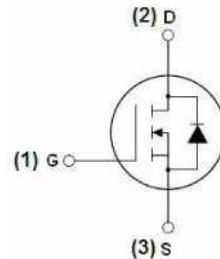




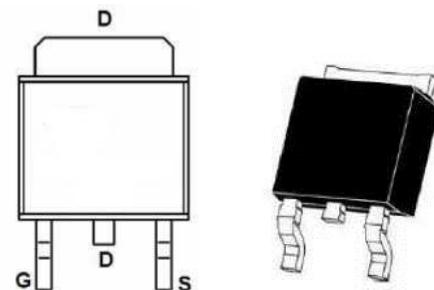
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60V ( $V_{DS}$ ) / 25A ( $I_D$ ) N-Channel Enhancement-Mode MOSFET



Schematic diagram



TO-252

## Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous <small>T<sub>c</sub> = 100°C</small>	$I_D$	25	A
		14	
Drain Current -Pulsed <sup>a</sup>	$I_{DM}$	60	A
Power Dissipation	$P_D$	45	W
Derating factor		0.3	W/ °C
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	°C
Single pulse avalanche energy (Note 5)	EAS	72	mJ
Thermal Resistance, Junction-to-Ambient <sup>1</sup> (Note2)	$R_{\theta JA}$	3.3	°C/W

**Absolute Maximum Ratings (TA=25°C unless otherwise noted)**

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	—	—	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	—	—	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V, V <sub>DS</sub> =0V	—	—	±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.2	1.6	2.5	V
Static Drain-Source On-Resistance	R <sub>DSS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =4.5 A	—	27	32	mΩ
Forward Transconductance	g <sub>fS</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =5A	11	—	—	S
Diode Forward Voltage (Note3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	—	—	1.2	V
Continuous Source Current (Note2)	I <sub>S</sub>		—	—	20	A
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, IF =20A di/dt = 100A/μs(Note3)	—	35	—	nS
Reverse Recovery Charge	Q <sub>rr</sub>		—	53	—	nC
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V,V <sub>DS</sub> =30V, f=1.0MHz	—	1500	—	pF
Output Capacitance	C <sub>oss</sub>		—	60	—	
Reverse Transfer Capacitance	C <sub>rss</sub>		—	25	—	
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =10V,V <sub>DS</sub> =30V, I <sub>D</sub> =4.5A	—	47	—	nC
Gate-Source Charge	Q <sub>gs</sub>		—	6	—	
Gate-Drain Charge	Q <sub>gd</sub>		—	14	—	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =30V, R <sub>L</sub> =6.7Ω R <sub>G</sub> =3Ω, V <sub>GS</sub> =10V	—	5	—	ns
Turn-on Rise Time	t <sub>r</sub>		—	2.6	—	
Turn-off Delay Time	t <sub>d(off)</sub>		—	16.1	—	
Turn-off Fall Time	t <sub>f</sub>		—	2.3	—	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

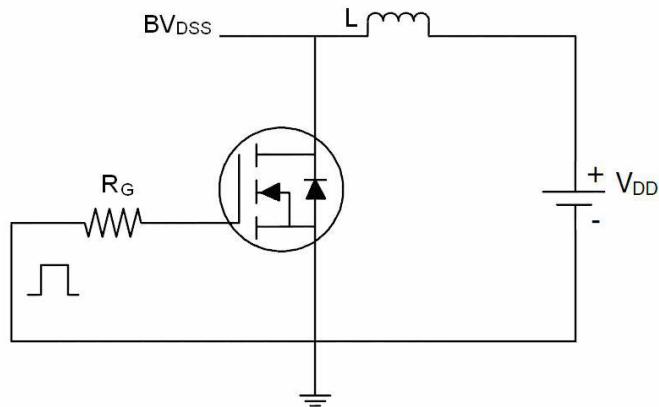
Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Pulse Test: Pulse Width ≤ 300μ ≤ 10 sec .
3. Surface Mounted on FR4 Board,s,t Duty Cycle ≤ 2%.
- 4.Guaranteed by design, not subject to production
5. EAS condition:Tj=25 ,VDD=30V,VG=10V,L=0.5mH,Rg=25Ω

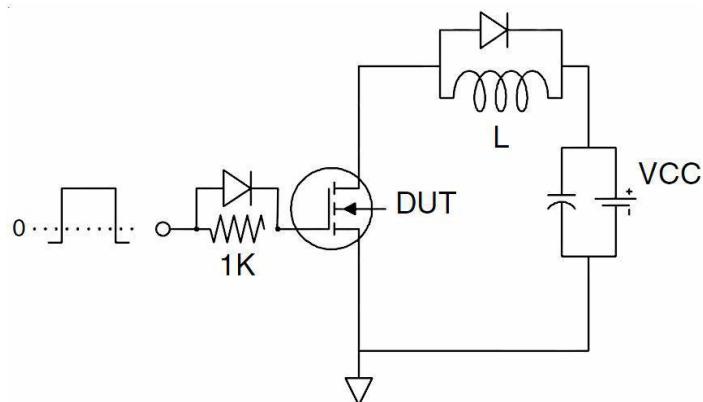


## Test Circuit

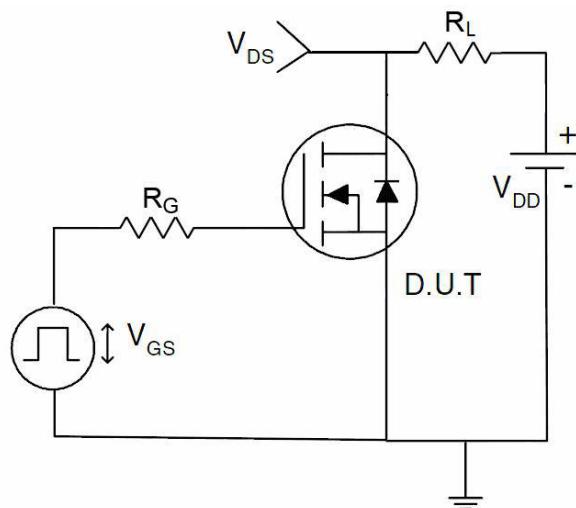
### 1) EAS test Circuit



### 2) Gate charge test Circuit



### 3) Switch Time Test Circuit

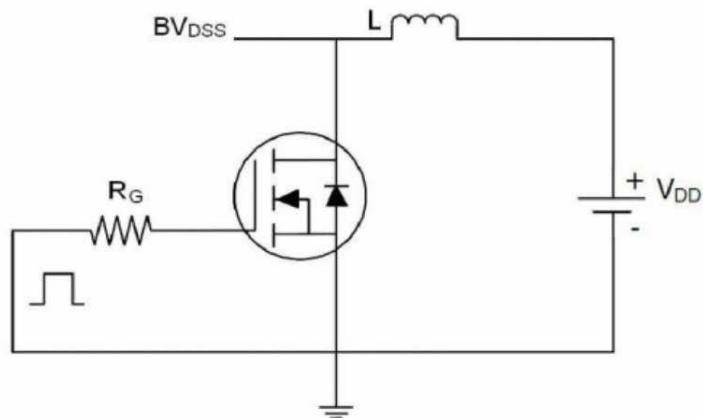




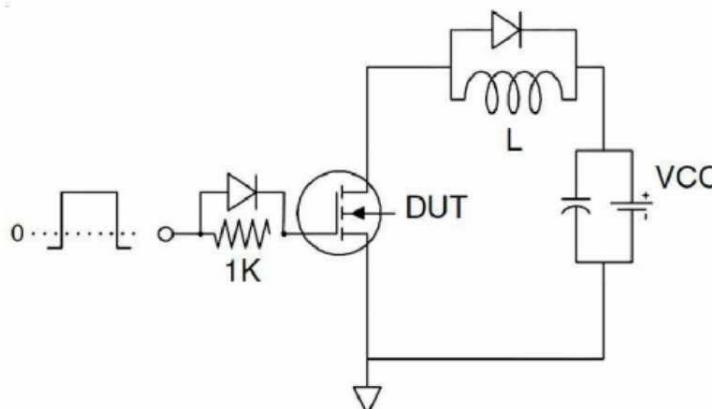
## Typical Electrical and Thermal Characteristics (Curves)

### Test Circuit

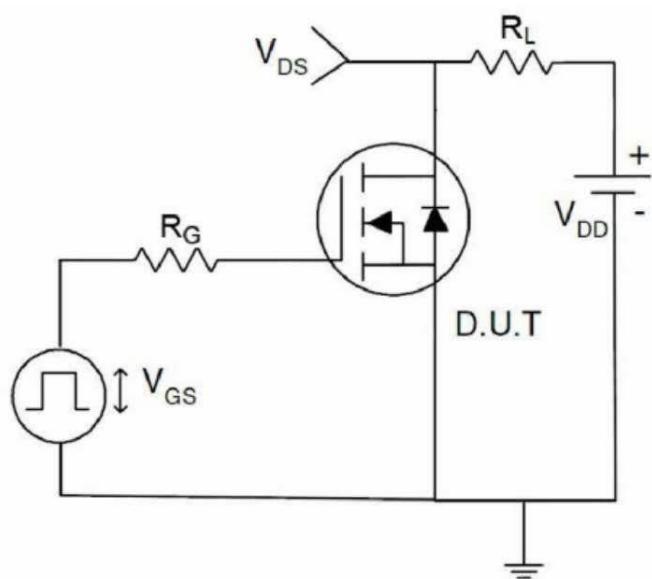
#### 1) EAS test Circuit



#### 2) Gate charge test Circuit



#### 3) Switch Time Test Circuit





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#### Typical Electrical and Thermal Characteristics (Curves)

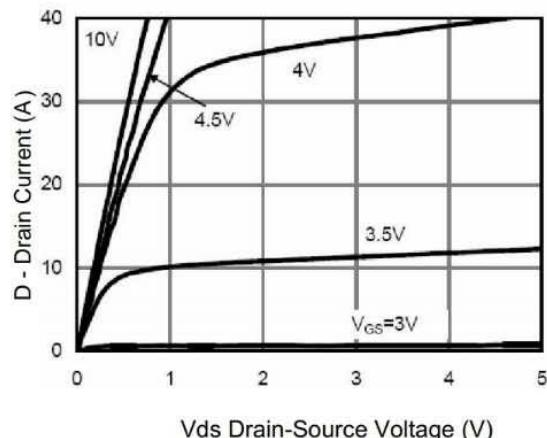


Figure 1 Output Characteristics

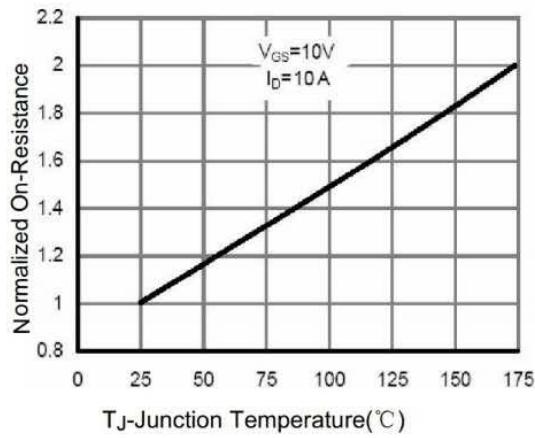


Figure 4 Rdson-Junction Temperature

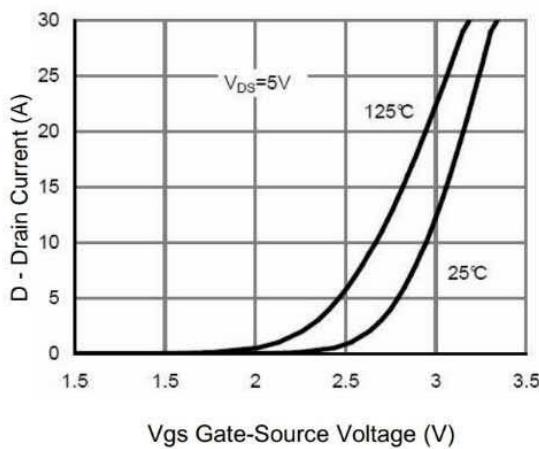


Figure 2 Transfer Characteristics

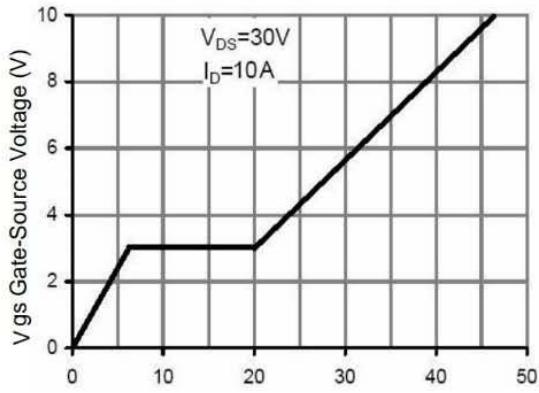


Figure 5 Gate Charge

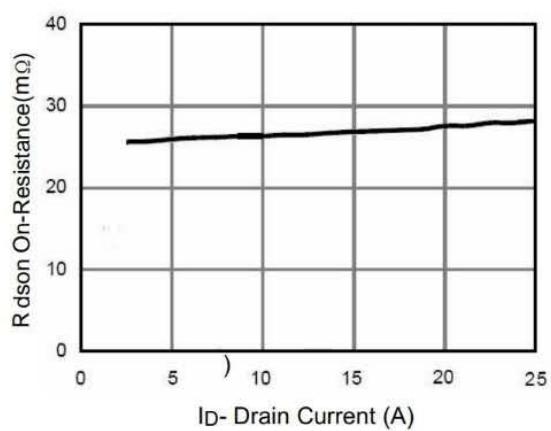


Figure 3 Rdson- Drain Current

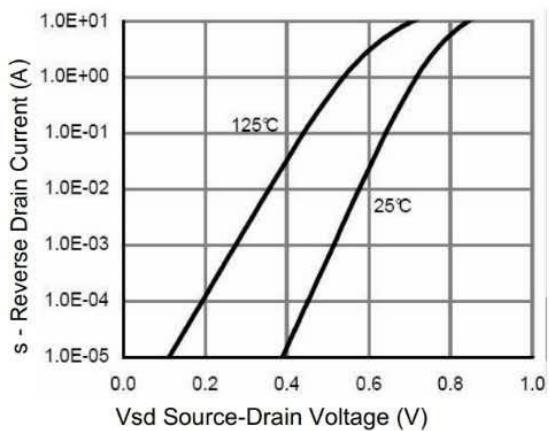


Figure 6 Source- Drain Diode Forward



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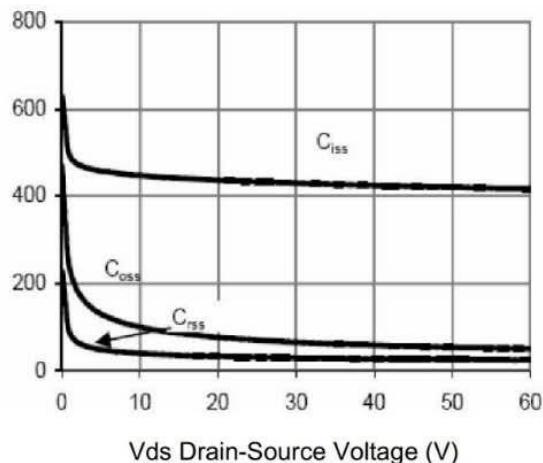


Figure 7 Capacitance vs  $V_{DS}$

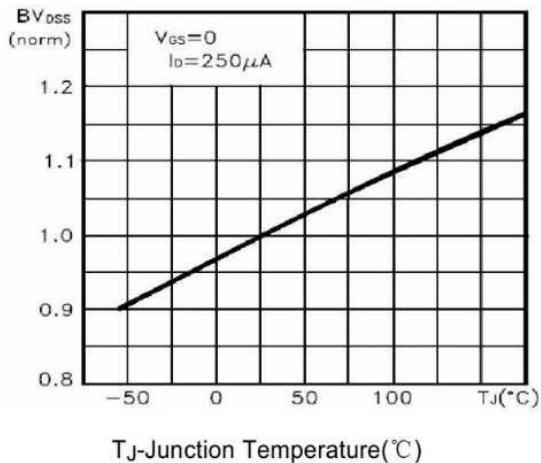


Figure 9  $BV_{DSS}$  vs Junction Temperature

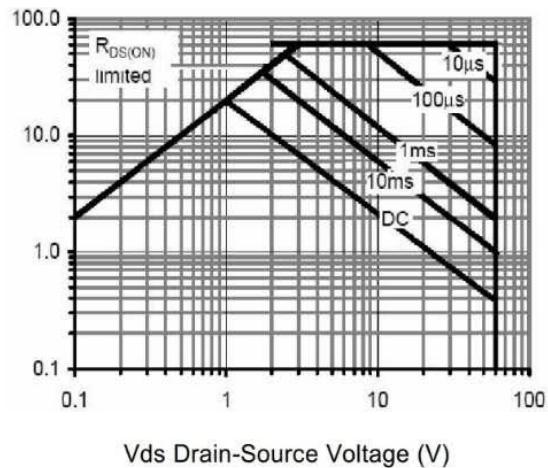


Figure 8 Safe Operation Area

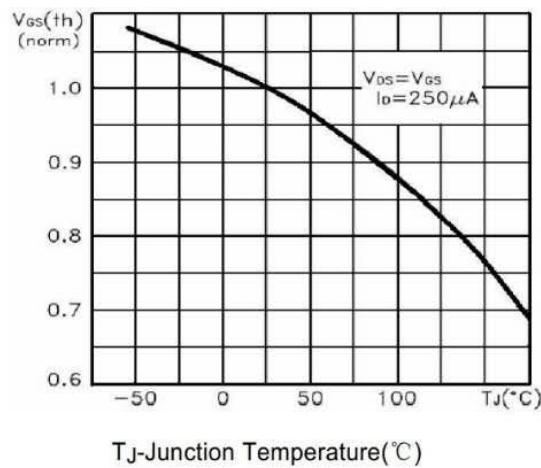


Figure 10  $V_{GS(th)}$  vs Junction Temperature

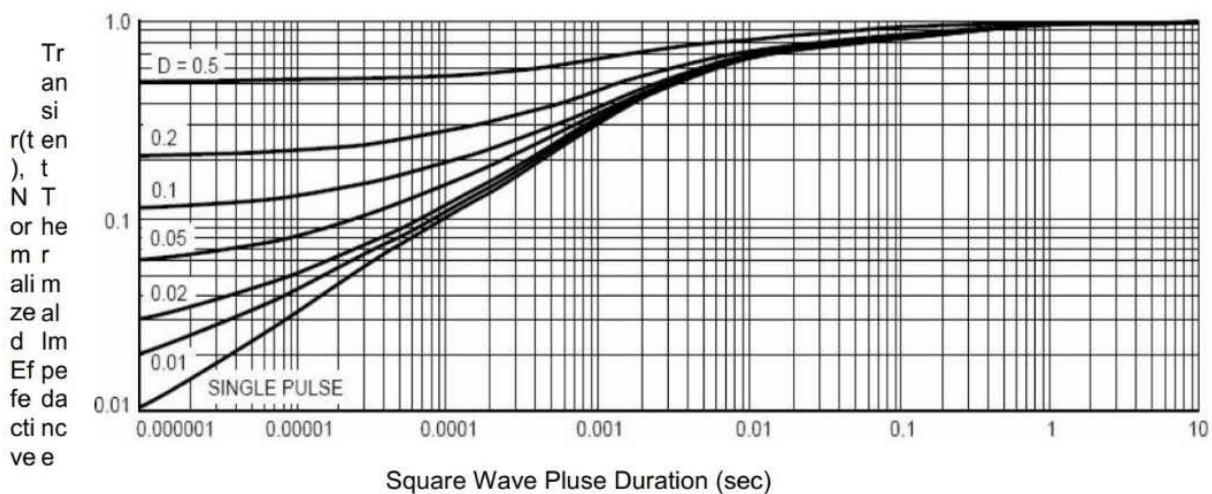
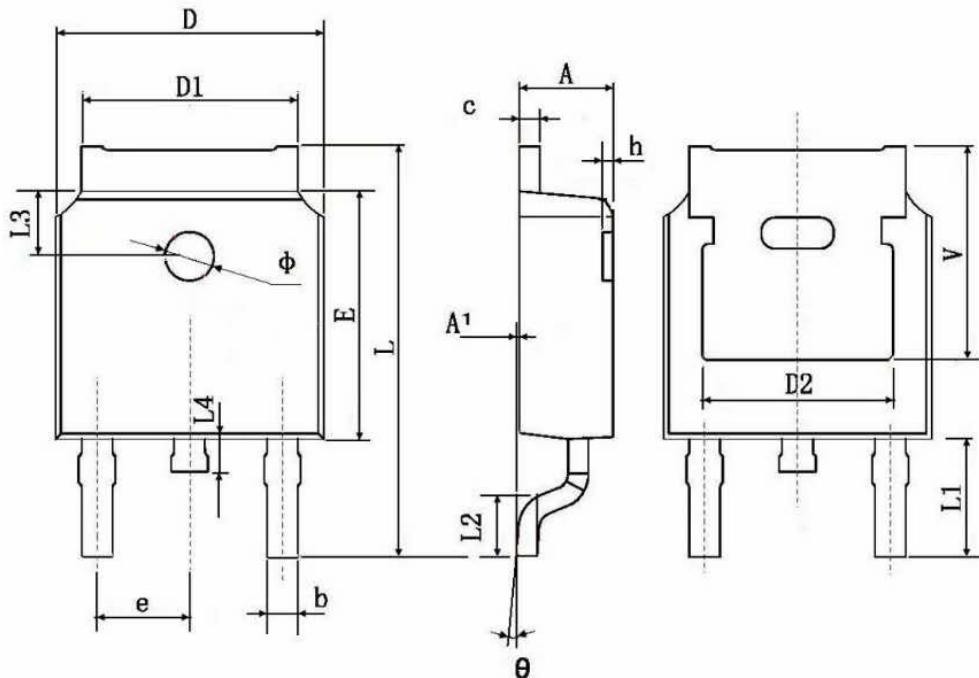


Figure 11 Normalized Maximum Transient Thermal Impedance



60V ( $V_{DS}$ ) / 30A ( $I_D$ ) N-Channel Enhancement-Mode MOSFET

TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
$\phi$	1.100	1.300	0.043	0.051
$\theta$	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	